

Memorandum 6M-3332-1

Page 1 of 2

Division 6 - Lincoln Laboratory  
Massachusetts Institute of Technology  
Lexington 73, Massachusetts

SUBJECT: CENTRAL COMPUTER EVALUATION, NO. 2, MARCH 7-18, 1955

TO: NORMAN TAYLOR

FROM: SAMUEL L. THOMPSON

DATE: JANUARY 27, 1955, REVISED MARCH 14, 1955

APPROVED:   
J. A. O'Brien

Abstract:

The second central computer evaluation test will take place on March 18, 1955. During this test, special emphasis will be placed on testing the memory. Less shock testing will be done. Otherwise, the test will be the same as the first central computer evaluation test.

1. Reliability. See the attached time schedule.
2. Power Off. Power (AC and DC) will be turned off for 15 minutes. The time required to get all of the reliability programs listed in the time schedule running again will be measured.
3. The reliability run will be repeated.
4. Shock tests. About 150 plug-in units will be vibrated. Shaking the plug-in units should also shake the tubes in the units. Only 100 tubes will be tapped individually.
5. Repeat the reliability test.

The results of this test will be included in the report that evaluates the central computer as of March 18, 1955. This report will also include the records of the computer's performance between March 7 and March 18, 1955

Central Computer Reliability Test

March 18, 1955

Run these programs for the length of this given:

<u>Program:</u>		<u>Time:</u>
RCC 01	"Hard Core"	5 min.
RCM 01	Card Machines	Run Once
RMM 2 04	Memory	15 min.
	Switch memories and repeat RMM 2 04	15 min.
RCM 01	Card Machines	Run Once
RCC 02	Program Element	15 min.
RCM 01	Card Machines	Run Once
RAE 01	Arithmetic Element	20 min.
Special Punch	Card Punch	5 min.
RMM 1 08	Memory	15 min.
RMM 2 07	Memory	15 min.
RAE 03	Arithmetic Element	5 min.

Total Time -- 2 hours

*S. L. Thompson*  
S. L. Thompson

SLT:rm

cc: <u>MIT</u>	<u>IBM at Poughkeepsie</u>	<u>IBM at Lexington</u>
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